

1048576-BIT(1048576-WORD BY 1-BIT) CMOS STATIC RAM

FUNCTION

The RAM works with an organization of 1048576-word by 1-bit, when $B1/\overline{B4}$ is high. And an organization of 262144-word by 4-bit is also obtained for reducing the test time, when $B1/\overline{B4}$ is low.

A write operation is executed during the \overline{S} low and \overline{W} low overlap time. In this period, address signals must be stable. When \overline{W} is low the Q terminal is maintained in the high impedance state, so it is possible to connect D and Q terminal directly.

In a read operation, after setting \overline{W} to high, and \overline{S} to low if the address signals are stable, the data is available at Q terminal.

When \overline{S} is high, the chip is the non-selectable state, disabling both reading and writing. In this case, the output is in the floating (high-impedance) state, useful for OR-tie

with other devices.

Signal \overline{S} controls the power-down features. When \overline{S} goes high, power dissipation is reduced extremely. The access time from \overline{S} is equivalent to the address access time.

FUNCTION TABLE

\overline{S}	\overline{W}	Mode	D	Q	I_{CC}
H	X	Not select	Hi-Z	Hi-Z	Stand by
L	L	Write	D_{in}	Hi-Z	Active
L	H	Read	Hi-Z	D_{out}	Active

Note: H: V_{IH} , L: V_{IL} , X: Don't care

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Units
V_{CC}	Supply voltage	With respect to GND	$-3.5^{\ast} \sim 7$	V
V_I	Input voltage		$-3.5^{\ast} \sim 7$	V
V_O	Output voltage		$-3.5^{\ast} \sim 7$	V
P_d	Power dissipation		1	W
T_{opr}	Operating temperature		$0 \sim 70$	$^{\circ}C$
T_{stg}	Storage temperature		$-65 \sim +150$	$^{\circ}C$

* Pulse width $\leq 20ns$, in case of DC: $-0.5V$

DC ELECTRICAL CHARACTERISTICS ($T_a = 0 \sim 70^{\circ}C$, $V_{CC} = 5V \pm 10\%$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Units
			Min	Typ	Max	
V_{IH}	High-level input voltage		2.4		$V_{CC} + 0.3$	V
V_{IL}	Low-level input voltage		-0.5^{\ast}		0.6	V
V_{OH}	High-level output voltage	$I_{OH} = -4mA$	2.4			V
V_{OL}	Low-level output voltage	$I_{OL} = 8mA$			0.4	V
I_I	Input current	$V_I = 0 \sim V_{CC} + 0.3V$			2	μA
I_{OZ}	Off-state output current	$V_I(s) = V_{IH}$, $V_O = 0 \sim V_{CC}$			10	μA
I_{CC1}	Supply current from V_{CC}	$V_I(s) = V_{IL}$, Output-open	AC (Min cycle)		120	mA
			DC		60	75
I_{CC2}	Standby current	$V_I(s) = V_{IH}$	AC (Min cycle)		40	mA
			DC		30	mA
I_{CC3}	Stand by current	$V_I(s) \geq V_{CC} - 0.2V$, other $V_I \leq 0.2V$ or $V_I \geq V_{CC} - 0.2V$		1	10	mA

* $-3.0V$ in case of AC (Pulse width $\leq 20ns$)

CAPACITANCE ($T_a = 0 \sim 70^{\circ}C$, $V_{CC} = 5V \pm 10\%$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Units
			Min	Typ	Max	
C_I	Input capacitance	$V_I = GND$, $V_I = 25mV_{rms}$, $f = 1MHz$			5	pF
C_O	Input output capacitance	$V_O = GND$, $V_O = 25mV_{rms}$, $f = 1MHz$			5	pF

Note 1: Current flowing into an IC is positive, out is negative.



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AC ELECTRICAL CHARACTERISTICS ($T_a = 0 \sim 70^\circ\text{C}$, $V_{CC} = 5V \pm 10\%$, unless otherwise noted)

(1) MEASUREMENT CONDITIONS

Input pulse level $V_{IH} = 3V, V_{IL} = 0V$
 Input rise and fall time 3ns
 Input timing reference level $V_{IH} = 2.4V, V_{IL} = 0.6V$
 Output timing reference level . . . $V_{OH} = 2V, V_{OL} = 0.8V$
 Output loads Fig. 1, Fig. 2

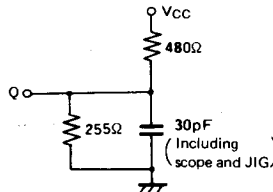


Fig. 1 Output load

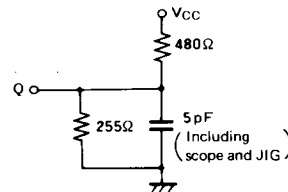


Fig. 2 Output load for ten, t_{dis}

(2) READ CYCLE

Symbol	Parameter	Limits						Units
		M5M51001-35			M5M51001-45			
		Min	Typ	Max	Min	Typ	Max	
$t_C(R)$	Read cycle time	35			45			ns
$t_a(A)$	Address access time			35			45	ns
$t_a(S)$	Chip select access time			35			45	ns
$t_V(A)$	Data valid time after address	5			5			ns
$t_{en}(S)$	Chip selection to output active	5			5			ns
$t_{dis}(S)$	Output disable time from \bar{S} high	0		20	0		20	ns
t_{pu}	Power-up time after chip selection	0			0			ns
t_{pd}	Power-down time after chip selection			35			45	ns

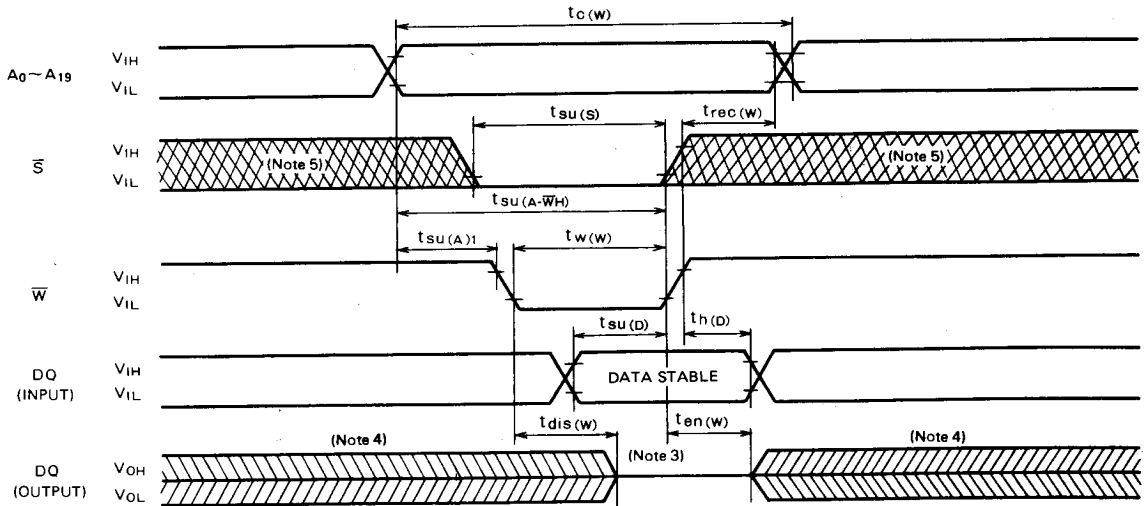
(3) WRITE CYCLE

Symbol	Parameter	Limits						Units
		M5M51001-35			M5M51001-45			
		Min	Typ	Max	Min	Typ	Max	
$t_C(W)$	Write cycle time	35			45			ns
$t_{su}(S)$	Chip select setup time	30			35			ns
$t_{su}(A)1$	Address setup time (\bar{W})	0			0			ns
$t_{su}(A)2$	Address setup time (\bar{S})	0			0			ns
$t_W(W)$	Write pulse width	30			35			ns
$t_{rec}(W)$	Write recovery time	5			5			ns
$t_{su}(D)$	Data setup time	15			20			ns
$t_h(D)$	Data hold time	0			0			ns
$t_{dis}(W)$	Output disable time from \bar{W}	0		15	0		15	ns
$t_{en}(W)$	Output enable time from \bar{W}	0			0			ns
$t_{su}(A-WH)$	Address to \bar{W} high	30			35			ns

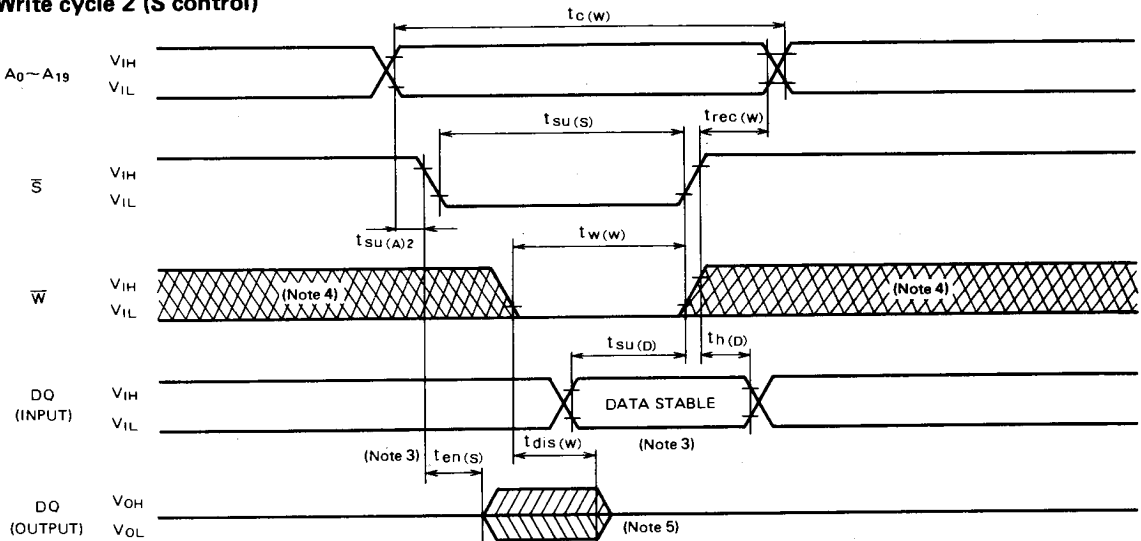
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(5) TIMING DIAGRAMS FOR WRITE CYCLE

Write cycle 1 (\bar{W} control)



Write cycle 2 (\bar{S} control)



Note 4: Hatching indicates the states don't care.

Note 5: When the falling edge of \bar{W} is simultaneously or prior to the falling edge of \bar{S} , the outputs are maintained in the high impedance.